

**Search Notes**

Application/Control No.

10/655,390

Examiner

Sun J. Lin

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	4	9/12/2005	JSL
716	5	9/12/2005	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	9/12/2005	JSL
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	9/16/2005	JSL
IEEE	9/12/2005	JSL
IEEE	9/17/2005	JSL